

2Mb CMOS STATIC SRAM

FEATURES

- High density SRAM module
- Organized as 262,144 x 8
- Access time 70 - 100ns
- Low power consumption
Standby: 25 μ W(typ.)
Operating: 200mW(typ.)
- Power supply voltage 5V \pm 10%
- TTL compatible inputs and outputs
- Fully static operation
- 32 pin DIP package
- JEDEC standard pinout
- MIL or commercial temperature range

Pin Configuration

NC	1	32	VCC
A16	2	31	A15
A14	3	30	A17
A12	4	29	WE
A7	5	28	A16
A6	6	27	A8
A5	7	26	A9
A4	8	25	A11
A3	9	24	OE
A2	10	23	A10
A1	11	22	OE
A0	12	21	IO8
IO1	13	20	IO7
IO2	14	19	IO6
IO3	15	18	IO5
GND	16	17	IO4

Pin Description

A0 - A17	Address Inputs
IO1 - IO8	Data Inputs/Outputs
CE	Chip Enable
OE	Output Enable
WE	Write Enable
VCC	Power Supply
GND	Ground

GENERAL DESCRIPTION

The ELPAQ EMS256Kx8C is a high performance 2Mb CMOS SRAM module organized as 262,144 bytes of 8 bits each, using two 1Mb SRAMs and a decoder. The EMS256Kx8C is packaged in a 32 lead 600 mil wide ceramic or plastic DIP package. The module is offered in a variety of temperature and speed combinations.

All inputs and outputs are TTL compatible and the module operates from a single 5V power supply. The EMS256Kx8C is a fully asynchronous SRAM and requires no clocks for operation. The module is also available in Low Power and Low Power with Data Retention versions for applications where low current and low stand-by voltages are required.

Writing data to the module is accomplished by bringing the chip enable (CE) and write enable (WE) inputs LOW. Data present on the eight I/O pins (IO₁ - IO₈) of the device is then written into the memory location specified by the address inputs (A₀ - A₁₇). Reading data from the device is accomplished by bringing chip enable (CE) and (OE) LOW while write enable remains inactive or HIGH. The data in the location specified by the address inputs will appear on the I/O pins.

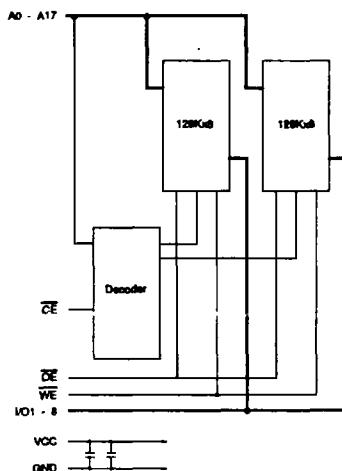
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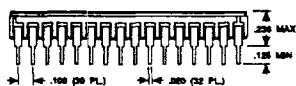
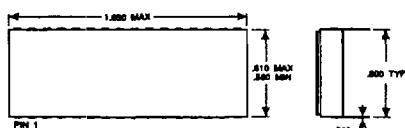
EMS256K8C

70 - 100ns

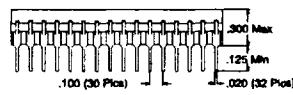
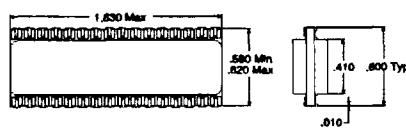
BLOCK DIAGRAM



PACKAGE OUTLINE



Package Type MO2, 32 Lead .600" Sidebrazed DIP



Package Type MO6, 32 Lead .600" Plastic DIP

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ABSOLUTE MAXIMUM RATINGS**OPERATING RANGES****Storage Temperature**

Ceramic Packages	-65°C to +150°C	Operating Temperature	0°C to +70°C
Plastic Packages	-55°C to +125°C	Commercial	-40°C to +85°C
		Industrial	-55°C to +125°C

Voltage and Current

Supply Voltage	-0.5 to +7.0V	Voltage and Current	
Input Voltage	-0.5 to Vcc+0.5V	Supply Voltage	4.5 to 5.5V
Input/Output Voltage	-0.5 to Vcc+0.5V	Input High Voltage	2.2 to Vcc+0.3V
Allowable Power Dissipation	1W	Input Low Voltage	-0.3 to 0.8V

Soldering Temperature*Time 260°C * 10s

FUNCTIONAL TRUTH TABLE

CE	OE	WE	Mode	I/O1 - 8	Vcc Current
H	X	X	Not Selected	High Z	ISB1, ISB2
L	H	H	Output Disable	High Z	ICC
L	L	H	Read	Data Out	ICC
L	X	L	Write	Data In	ICC

CAPACITANCE (Ta=25°C, f=1MHz)

Item	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Input Capacitance	C _{IN}	V _{IN} = 0V	15	25	pF	
Input/Output Capacitance	C _{IO}	V _{I/O} = 0V	20	25	pF	

Note: This parameter is sample tested and not 100% tested.

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DC CHARACTERISTICS (Vcc=5V±10%, Ta=Topr)

Item	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Input Leakage Current	IIL	VIN=GND or VCC	-10		10	µA
Output Leakage Current	IOL	V _{IO} =GND or VCC, \overline{CE} =VIH \overline{OE} =VIH or \overline{WE} =VIL	-10		10	µA
Average Operating Current	ICC	Min. Cycle, Iout=0mA		40	70	mA
Standby Current	ISB1	$\overline{CE} \geq VCC-0.2V$, $VIN \geq VCC-0.2V$	0.005		1.5	mA
	ISB2	$\overline{CE}=VIH$, $VIN=VIL$ or VIH		2	5	mA
Output High Voltage	VOH	I _{OH} =-1.0mA		2.4		V
Output Low Voltage	VOL	I _{OL} =2.1mA			0.4	V

AC CHARACTERISTICS (Vcc=5V±10%, Ta=Topr)**AC Test Conditions**

Item	Condition
Input Pulse High Level	VIH=3V
Input Pulse Low Level	VIL=0V
Input Pulse Rise Time	tr=5ns
Input Pulse Fall Time	tf=5ns
Input and Output Timing Level	1.5V
Output Load	Fig. 1

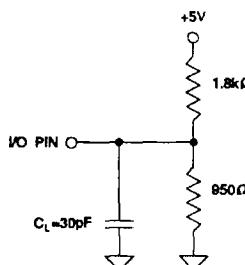
Output Load

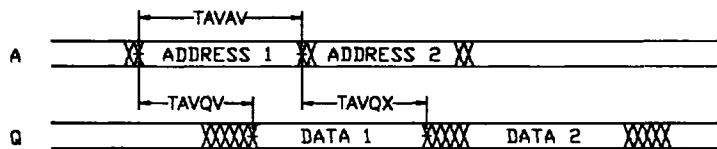
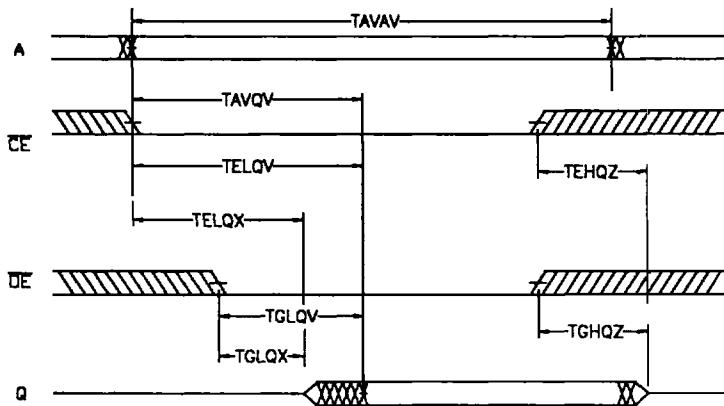
Fig. 1

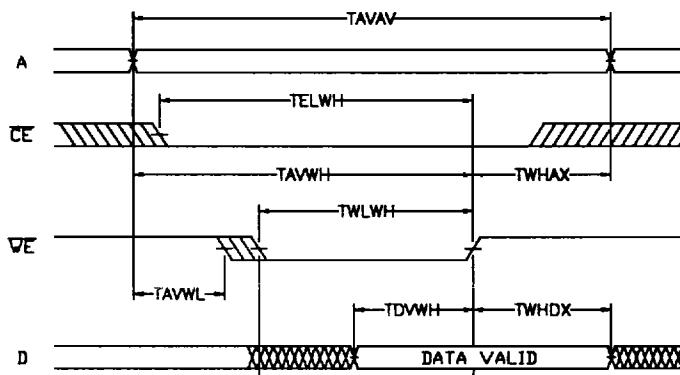
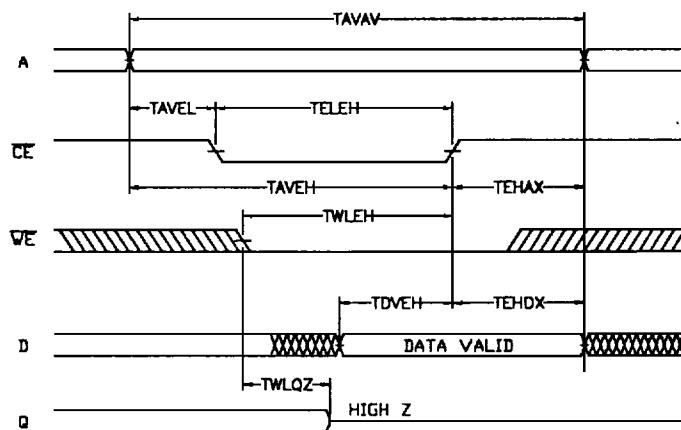
ELPAQA division of **ELMO Semiconductor Corp.****EMS256K8C****70 - 100ns****Read Cycle**

Item	Symbol	-70		-85		-100		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Read Cycle Time	TAVAV	70		85		100		ns
Address Access Time	TAVQV		70		85		100	ns
Chip Enable Access Time	TELQV		70		85		100	ns
Output Enable to Output Valid	TGLQV		40		45		50	ns
Chip Enable to Output in High Z	TEHQZ		30		30		35	ns
Chip Enable to Output in Low Z	TELQX	15		15		15		ns
Output Disable to Output in High Z	TGHQZ		25		25		35	ns
Output Enable to Output In Low Z	TGLQX	5		5		5		ns
Output Hold from Address Change	TAVQX	10		10			15	ns

Write Cycle

Item	Symbol	-70		-85		-100		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Write Cycle Time	TAVAV	70		85		100		ns
Address Valid to End of Write	TAVWH	60		75		75		ns
Chip Enable to End of Write	TELWH	65		75		75		ns
	TWLEH	65		75		75		ns
Data to Write Time Overlap	TDVWH	30		30		40		ns
	TDVEH	30		30		40		ns
Data Hold Time from Write	TWHDX	0		0		0		ns
	TEHDX	0		0		0		ns
Write Pulse Width	TWLWH	50		60		70		ns
	TELEH	50		60		70		ns
Address Set-up Time	TAVWL	0		0		0		ns
	TAVEL	0		0		0		ns
Write Recovery Time	TWHAX	5		5		5		ns
	TEHAX	5		5		5		ns
Write to Output in High Z	TWLQZ		25		30		30	ns
Output Active from End of Write	TWHQX	5		5		10		ns

Timing Diagrams**Read Cycle Timing****Read Cycle 1: $\overline{CE}=\overline{OE}=VIL$, $\overline{WE}=VIH$** **Read Cycle 2: $\overline{WE}=VIH$** 

Write Cycle Timing**Write Cycle 1: \overline{WE} Control****Write Cycle 2: \overline{CE} Control**

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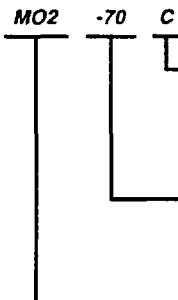
EMS256K8C

70 - 100ns

NOTES:

ORDERING INFORMATION

EMS256K8C



Temperature Range

C = Commercial (0 - 70°C)
I = Industrial (-40 - +85°C)
D = MIL Temp (-55 - +125°C)
M = MIL Screen (-55 - +125°C)

Speed

-70 = 70ns Access Time
-85 = 85ns Access Time
-100 = 100ns Access Time

Package

MO2 = .600" 32 Lead Ceramic DIP
MO6 = .600" 32 Lead Plastic DIP